

Advanced Small Signal MOSFET 2N7000BU/2N7000TA

FEATURES

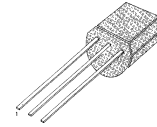
- Fast Switching Times
- Improved Inductive Ruggedness
- Lower Input Capacitance
- Extended Safe Operating Area
- Improved High Temperature Reliability

$$BV_{DSS} = 60 \text{ V}$$

$$R_{DS(on)} = 5.0 \, \Omega$$

$$I_D = 200 \text{ mA}$$

TO-92



1.Source 2. Gate 3. Drain

Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	60	V
I_D	Continuous Drain Current ($T_C=25^\circ\text{C}$)	200	mA
	Continuous Drain Current ($T_C=100^\circ\text{C}$)	110	
I_{DM}	Drain Current-Pulsed ^①	1000	mA
V_{GS}	Gate-to-Source Voltage	± 30	V
P_D	Total Power Dissipation ($T_C=25^\circ\text{C}$)	400	mW
	Linear Derating Factor	3.2	mW/ $^\circ\text{C}$
T_J, T_{STG}	Operating Junction and Storage Temperature Range	- 55 to +150	$^\circ\text{C}$
T_L	Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5-seconds	300	

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient	--	312.5	$^\circ\text{C}/\text{W}$

Electrical Characteristics (T_C=25°C unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV _{DSS}	Drain-Source Breakdown Voltage	60	--	--	V	V _{GS} =0V, I _D =250μA
V _{GS(th)}	Gate Threshold Voltage	0.3	--	3.9	V	V _{DS} = V _{GS} , I _D =250μA
		0.4	--	2.2		V _{DS} = V _{GS} , I _D =1mA
I _{GSS}	Gate-Source Leakage , Forward	--	--	100	nA	V _{GS} =15V
	Gate-Source Leakage , Reverse	--	--	-100		V _{GS} =-15V
I _{DSS}	Drain-to-Source Leakage Current	--	--	1	μA	V _{DS} =60V
		--	--	1000		V _{DS} =45V, T _C =125°C
R _{DS(on)}	Static Drain-Source On-State Resistance ②	--	--	5.0	Ω	V _{GS} =10V, I _D =0.5A
g _{fs}	Forward Transconductance ②	0.1	0.3	--	S	V _{DS} =15V, I _D =0.5A
C _{iss}	Input Capacitance	--	30	--	pF	V _{GS} =0V, V _{DS} =25V, f =1MHz
C _{oss}	Output Capacitance	--	12	--		
C _{rss}	Reverse Transfer Capacitance	--	3.0	--		
t _{d(on)}	Turn-On Delay Time	--	--	10	ns	V _{DD} =30V, I _D =0.5A, R _G =15Ω ② ③
t _r	Rise Time	--	--	10		
t _{d(off)}	Turn-Off Delay Time	--	--	10		
t _f	Fall Time	--	--	10		

Notes ;

- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- ② Pulse Test : Pulse Width = 250μs, Duty Cycle ≤ 2%
- ③ Essentially Independent of Operating Temperature

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